4/17/2012

RELIABILITY MONITOR REPORT
FOR

MFN 3µm Silicon Gate CMOS (S3)

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

This Report was prepared by
Maxim Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX3250EAI+	MAX4582AUE+

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 17304 QUANTITY: 277 FAILS: 1 FITS: 6.6

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2011 and 3/31/2012 .

Process Information:

Process Description: MFN 3µm Silicon Gate CMOS (S3)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1041	MAX3250EAI+	135C	1000 HRS	77	0	SF6AAJQ1
HIGH TEMP OP LIFE	1041	MAX3250EAI+	135C	1000 HRS	45	0	SF6AAJQ2
HIGH TEMP OP LIFE	1041	MAX3250EAI+	135C	1000 HRS	75	0	SF6AAJQ3
HIGH TEMP OP LIFE	1042	MAX4582AUE+	135C	500 HRS	80	1	NO7BBA762BD
				Total:		**1**	

UNBIASED MOISTURE RESISTANCE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
MOISTURE SOAK	1041	MAX3250EAI+	85 C/85% R.H.	1000 HRS	15	0	SF6AAJQ1
				Total:		**0**	

FAILURE RATE: MTTF (YRS): 17304 QUANTITY: 277 FAILS: 1 FITS: 6.6